	Application No.	Applicant(s)
Notice of Allowability	10/711,536	HSUAN ET AL.
	Examiner	Art Unit
	Monica D. Harrison	2813
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.		
1. This communication is responsive to <u>applicant's phone interview and email correspondence with Belinda Lee on 9/29/06.</u>		
2. The allowed claim(s) is/are <u>1-9</u> .		
<ul> <li>3. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).</li> <li>a) All b) Some* c) None of the: <ol> <li>Certified copies of the priority documents have been received.</li> <li>Certified copies of the priority documents have been received in Application No.</li> <li>Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).</li> </ol> </li> <li>* Certified copies not received:</li> </ul>		
Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.  THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		
4. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.		
<ul> <li>5. CORRECTED DRAWINGS ( as "replacement sheets") must be submitted. <ul> <li>(a) including changes required by the Notice of Draftsperson's Patent Drawing Review ( PTO-948) attached</li> <li>1) hereto or 2) to Paper No./Mail Date</li> <li>(b) including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date</li> <li>Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).</li> </ul> </li> <li>6. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.</li> </ul>		
Attachment(s)  1. ☑ Notice of References Cited (PTO-892)  2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)  3. ☐ Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date  4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	9.	(PTO-413), te

## **EXAMINER'S AMENDMENT**

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

- 1. Authorization for this examiner's amendment was given in a telephone interview with Belinda Lee on Friday, September 29, 2006.
  - 2. Claims 10-19 have been cancelled.
  - 3. Claim 1 shall now read as follows:

A wafer level chip scale package structure process, comprising:

providing a glass substrate having a first surface and a second surface, wherein an interconnect pattern is disposed on the first surface of the glass substrate;

providing a wafer comprising a plurality of chips and having an active surface and a back surface, wherein a plurality of bumps is disposed on the active surface of the wafer;

flipping the wafer, so that the active surface of the wafer faces the first surface of the glass substrate;

disposing the wafer on the glass substrate and connecting the active surface of the wafer to the first surface of the glass substrate through attachment of the bumps and the interconnect pattern;

performing a first dicing step whereby the wafer is cut-dicing the wafer; drilling the glass substrate to form a plurality of through holes; and Art Unit: 2813

subsequent to the first dicing step, forming a plurality of via plugs in the through plated holes in the glass substrate; and

performing a second dicing step to diceing the glass substrate and the interconnect pattern at the through hole to form a plurality of chip scale package structures with plated/or metal or metallic layers on the side edges of the substrate.

## Allowable Subject Matter

4. Claims 1-9 are allowed over the prior art of record.

## Reasons For Allowance

5. The following is an examiner's statement of reasons for allowance: The prior art does not disclose nor fairly suggest a wafer chip scale package structure process and described in the independent claim.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

## Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Monica D. Harrison whose telephone number is 571-272-1959. The examiner can normally be reached on M-F 7:00am-3:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Carl Whitehead Jr. can be reached on 571-272-1702. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/711,536 Page 4

Art Unit: 2813

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <a href="http://pair-direct.uspto.gov">http://pair-direct.uspto.gov</a>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Monica D. Harrison AU 2813

mdh

September 29, 2006